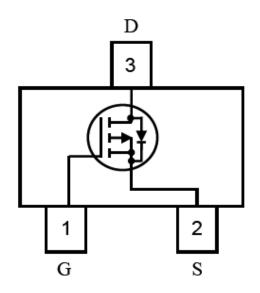


P-Channel MOSFET MEM2303X

General Description

MEM2303XG Series P-channel enhancement mode field-effect transistor ,produced with high cell density DMOS trench technology, which is especially used to minimize on-state resistance. This device particularly suits low voltage applications, and low power dissipation, and low power dissipation in a very small outline surface mount package.

Pin Configuration



Features

-30V/-4.2A

 $R_{DS(ON)} = 55 \text{m} \Omega @ V_{GS} = -10 \text{V}, I_D = -4.2 \text{A}$

 $R_{DS(ON)} = 62m\Omega @ V_{GS} = -4.5V, I_D = -4A$

 $R_{DS(ON)} = 72 \text{m}\Omega @ V_{GS} = -2.5 \text{V}, I_D = -1 \text{A}$

- High Density Cell Design For Ultra Low On-Resistance
- Subminiature surface mount package:SOT23

Typical Application

- Power management
- Load switch
- Battery protection

Absolute Maximum Ratings

	Symbol	Ratings	Unit		
Drain-Source Voltage		V_{DSS}	-30V	V	
Gate-Source Voltage		V_{GSS}	±12	V	
Drain Current	T _A =25℃		-4.2	А	
	T _A =70°C	l _D	-3.5		
Pulsed Drain Current ^{1,2}		I _{DM}	-30	Α	
Total Power Dissipation	T _A =25℃	D	1.4	W	
	T _A =70°C	P_{D}	1		
Operating Temperature Range		T _{Opr}	150	$^{\circ}$	
Storage Temperature Range		T _{stg}	-65/150	${\mathbb C}$	



Thermal Characteristics

Parameter		Symbol	TYP.	MAX.	Unit
Thermal Resistance,	t≤10s	D	65	90	°C/W
Junction-to-Ambient	12105	$R_{ hetaJA}$	05	90	C/VV
Thermal Resistance,	Stoody State	R _{eJA}	85	125	°C /W
Junction-to-Ambient	Steady-State				
Thermal Resistance,	Stoody State	$R_{ heta JL}$	43	60	°C/W
Junction-to-Lead	Steady-State				

Electrical Characteristics

Parameter	Symbol	Test Condition	Min	Туре	Max	Unit			
Static Characteristics									
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} =0V, I_D =-250 μ A	-30	-35	1	V			
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.7	-1.0	-1.3	V			
Gate-Body Leakage	1	V_{DS} =0V, V_{GS} =12V	-	3	100	nA			
Gate-Body Leakage	I_{GSS}	V_{DS} =0V, V_{GS} =-12V	-	-3	-100	nA			
Zero Gate Voltage Drain Current	I_{DSS}	V _{DS} =-24V V _{GS} =0V	-	-3.5	-1000	nA			
	R _{DS(ON)1}	V _{GS} =-10V,I _D =-4.2A	-	55	63	mΩ			
Static Drain-Source On-Resistance	R _{DS(ON)2}	V_{GS} =-4.5 V , I_D =-4 A	-	62	70	mΩ			
	R _{DS(ON)3}	V_{GS} =-2.5V, I_{D} =-1A	-	72	90	mΩ			
Forward Transconductance	g FS	$V_{DS} = -5 \text{ V}, I_{D} = -2.8 \text{ A}$	7	11	-	S			
Maximum Body-Diode Continuous Current	I _s		-	ı	-2.2	А			
Source-drain(diode forward) voltage	V_{SD}	V _{GS} =0V,I _S =-1A	-	-0.8	-1.0	V			
	Dy	namic Characteristics							
Input Capacitance	Ciss	V _{GS} =0V, V _{DS} =-15V,	-	954	-				
Output Capacitance	Coss	f=1MHz	-	115	-	pF			
Reverse Transfer Capacitance	Crss	I-TIVITIZ	-	77	-				
Gate resistance	Rg	V_{GS} =0V, V_{DS} =0V, f=1MHz	-	6	-	Ω			
	Sw	itching Characteristics							
Turn-On Delay Time	td(on)		-	6.5	-				
Rise Time	tr	V _{GS} =-10V,V _{DS} =-15V,	-	3.5					
Turn-Off Delay Time	td(off)	R_L =3.6 Ω , R_{GEN} =6 Ω	-	38	-	ns			
Fall-Time	tf		-	12	-				
Total Gate Charge Q		V _{DS} = -15 V,	-	9.5	-				
Gate-Source Charge	Qgs	$V_{GS} = -4.5 V$,	-	2	-	nc			
Gate-Drain Charge	Qgd	I _D = -4A	-	3	-				

- 1. Pulse width limited by Max. junction temperature.
- 2_{\times} Pulse width <300us , duty cycle <0.5%.



Typical Performance Characteristics

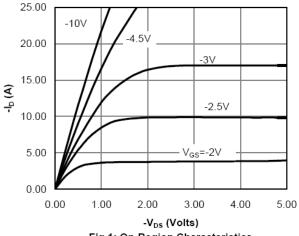


Fig 1: On-Region Characteristics

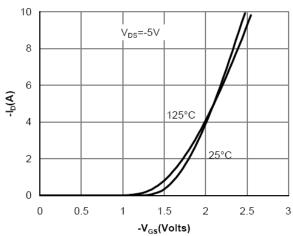


Figure 2: Transfer Characteristics

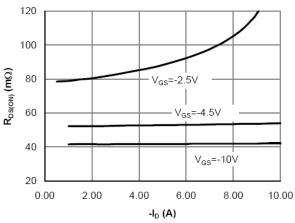


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

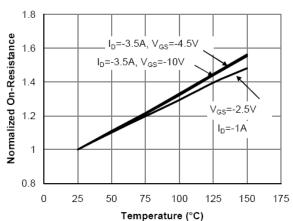


Figure 4: On-Resistance vs. Junction
Temperature

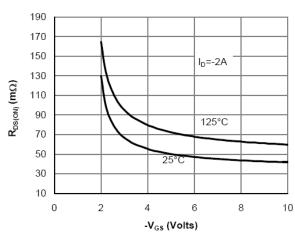


Figure 5: On-Resistance vs. Gate-Source Voltage

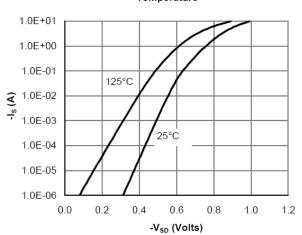


Figure 6: Body-Diode Characteristics



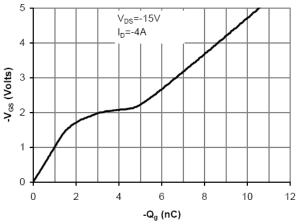


Figure 7: Gate-Charge Characteristics

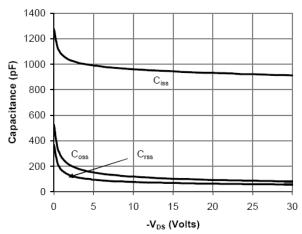


Figure 8: Capacitance Characteristics

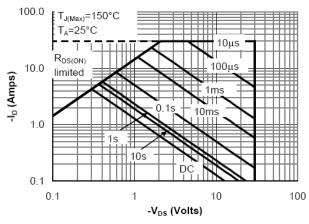


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

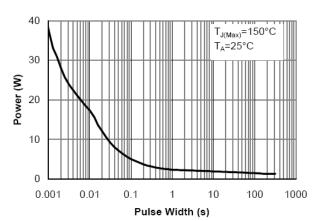


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

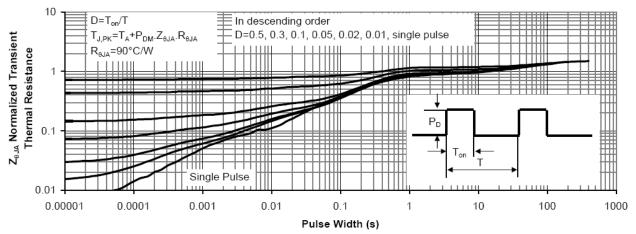
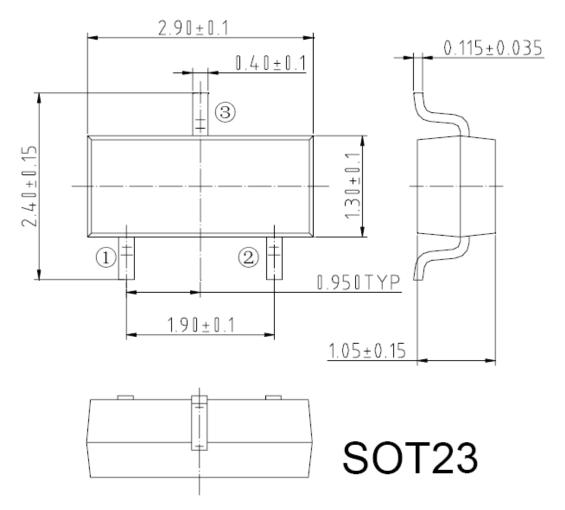


Figure 11: Normalized Maximum Transient Thermal Impedance



Package Information





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